## **PRODUCT / PROCESS CHANGE INFORMATION**

1. PCI basic data		
1.1 Company		STMicroelectronics International N.V
1.2 PCI No.		AMG/18/10705
1.3 Title of PCI		Test Flow optimization on A3G4250D and A3G4250DTR.
1.4 Product Category		A3G4250D and A3G4250DTR (Gyro)
1.5 Issue date		2018-02-14

2. PCI Team	
2.1 Contact supplier	
2.1.1 Name	ROBERTSON HEATHER
2.1.2 Phone	+1 8475853058
2.1.3 Email	heather.robertson@st.com
2.2 Change responsibility	
2.2.1 Product Manager	Andrea Mario ONETTI
2.1.2 Marketing Manager	Marco FERRARESI
2.1.3 Quality Manager	Michele CALDERONI

3. Change		
3.1 Category	3.2 Type of change	3.3 Manufacturing Location
Method (EWS-FT)	Different test flow (step removal, step order change, temperature change, quality control steps optimization, test time reduction, etc) if test flow is not defined by Customer.	MALTA

4. Description of change		
	Old	New
4.1 Description	Cold test is performed at Final Test in manufacturing flow.	Cold test is removed from Final Test and performed at EWS level on ASIC wafer. Introduction of IR reflow + THS (Temperature Humidity Storage) in the manufacturing flow.
4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?	No Impact.	

5. Reason / motivation for change	
5.1 Motivation	The notified change on Testing Flow for A3G4250D and A3G4250DTR products ensures to optimize the whole manufacturing flow.
5.2 Customer Benefit	SERVICE IMPROVEMENT

6. Marking of parts / traceability of change		

	7. Timing / schedule
7.1 Date of qualification results	2018-03-31
7.2 Intended start of delivery	2018-05-07
7.3 Qualification sample available?	Upon Request

8. Qualification / Validation			
8.1 Description			
8.2 Qualification report and qualification results	In progress	Issue Date	

## 9. Attachments (additional documentations)

10705 Public product.pdf

10. Affected parts		
10. 1 Current		10.2 New (if applicable)
10.1.1 Customer Part No	10.1.2 Supplier Part No	10.1.2 Supplier Part No
	A3G4250DTR	



## **Public Products List**

Publict Products are off the shelf products. They are not dedicated to specific customers, they are available through ST Sales team, or Distributors, and visible on ST.com

PCI Title : Test Flow optimization on A3G4250D and A3G4250DTR.

PCI Reference : AMG/18/10705

Subject : Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

	A3G4250D	A3G4250DTR	
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